FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			ATTY DOCKET NO. 35.C14272	APPLICATION NO. 09/512,360	
			APPLICANT HIDESHI KAWASAKI		
			FILING DATE February 24, 2000	GROUP 2	817_
			U.S. PATENT DOCUMENTS		
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME OF E V	CLASS SUBCLASS	FILING DATE
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		<u> </u>	FOREIGN PATENT DOCUMENTS		
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
196	9-134666	5/20/97	Japan		Abstract
MA	7-235255	9/5/95	Japan		Abstract
KJL	0 660 357 A1	6/28/95	Japan		English
		OTHER DOCUMEN	IT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		
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*EXAMINER: Initial if reference considered, whether or not challens in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.